Semiconductor Electronics: Materials, Devices and

OBJECTIVE TYPE QUESTIONS



Multiple Choice Questions (MCQs)

1. The equivalent resistance of the circuit shown in figure between the points A and B if

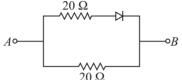


(a) 10Ω

(b) 20Ω

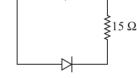
(c) 5Ω

(d) 40Ω

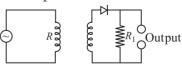


- **2.** Which of the following statements is correct?
- (a) Hole is an antiparticle of electron.
- (b) Hole is a vacancy created when an electron leaves a covalent bond.
- (c) Hole is the absence of free electrons.
- (d) Hole is an artificially created particle.
- 3. Which of the following statements is incorrect for the depletion region of a diode?
- (a) There are mobile charges exist.
- (b) Equal number of holes and electrons exist, making the region neutral.
- (c) Recombination of holes and electrons has taken place.
- (d) None of these.
- **4.** In an unbiased p-n junction, holes diffuse from the p-region to n-region because
- (a) free electrons in the *n*-region attract them
- (b) they move across the junction by the potential difference
- (c) hole concentration in *p*-region is more as compared to n-region
- (d) all of these.
- 5. A potential barrier of 0.3 V exists across a p-n junction. If the depletion region is 1 μm wide, what is the intensity of electric field in this region?
- (a) $2 \times 10^5 \text{ V m}^{-1}$
- (b) $3 \times 10^5 \text{ V m}^{-1}$
- $(c)~4\times10^5~V~m^{-1}$
- (d) $5 \times 10^5 \text{ V m}^{-1}$
- 6. The dominant mechanism for motion of charge carriers in forward and reverse biased silicon p-n junction are

- (a) drift in forward bias, diffusion in reverse
- (b) diffusion in forward bias, drift in reverse bias
- (c) diffusion in both forward and reverse bias
- (d) drift in both forward and reverse bias.
- 7. When the voltage drop across a p-njunction diode is increased from 0.65 V to 0.70 V, the change in the diode current is 5 mA. The dynamic resistance of the diode is
- (a) 20Ω
- (b) 50Ω (c) 10Ω
- In the circuit shown if drift current for the diode is 20 µA, the potential difference across the diode is
- (a) 2 V
- (b) 4.5 V
- (c) 4 V
- (d) 2.5 V



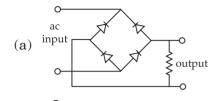
- **9.** If a small amount of antimony is added to germanium crystal
- (a) its resistance is increased
- (b) it becomes a *p*-type semiconductor
- (c) there will be more free electrons than holes in the semiconductor
- (d) none of these.
- 10. A sinusoidal voltage of rms value 220 V is applied to a diode and a resistor R in the circuit shown in figure, so that half wave rectification occurs. If the diode is ideal, what is the rms voltage across R_1 ?

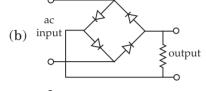


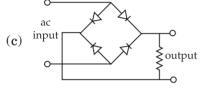
- (a) $55\sqrt{2} \text{ V}$
- (b) 110 V
- (c) $110\sqrt{2} \text{ V}$
- (d) $220\sqrt{2} \text{ V}$
- 11. If the energy of a proton of sodium light $(\lambda = 589 \text{ nm})$ equals the band gap of

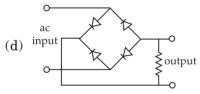
semiconductor, the minimum energy required to create hole electron pair

- (a) 1.1 eV
- (b) 2.1 eV (c) 3.2 eV
- (d) 1.5 eV
- 12. Which of the following circuits provides full wave rectification of an ac input?



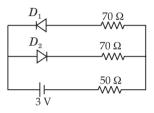






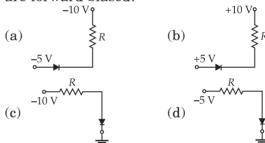
- 13. Carbon, silicon and germanium have four valence electrons each. These are characterised by valence and conduction bands separated by energy band gap respectively equal to $(E_g)_{\mathcal{C}}$, $(E_g)_{Si}$ and $(E_g)_{Ge}$. Which of the following statements is true?
- (a) $(E_g)_{Si} < (E_g)_{Ge} < (E_g)_{Ce}$
- (b) $(E_g)_{\rm C} < (E_g)_{\rm Ge} < (E_g)_{\rm Si}$
- (c) $(E_g)_{C} > (E_g)_{Si} > (E_g)_{Ge}$
- (d) $(E_g)_C = (E_g)_{Si} = (E_g)_{Ge}$
- 14. A forward biased diode is
- (b) -4 V -3 V
- (c) 3 V 5 V
- (d) -2 V +2 V
- 15. Which of the following equations correctly represents the temperature variation of energy gap between the conduction and valence bands for Si?
- (a) $E_g(T) = 0.70 2.23 \times 10^{-4} T \text{ eV}$ (b) $E_g(T) = 0.70 + 2.23 \times 10^{-4} T \text{ eV}$

- (c) $E_g(T) = 1.10 3.60 \times 10^{-4} T \text{ eV}$ (d) $E_g(T) = 1.10 + 3.60 \times 10^{-4} T \text{ eV}$
- 16. The maximum wavelength of electromagnetic radiation, which can create a hole-electron pair in germanium. (Given that forbidden energy gap in germanium is 0.72 eV)
- (a) $1.7 \times 10^{-6} \text{ m}$
- (b) $1.5 \times 10^{-5} \,\mathrm{m}$
- (c) 1.3×10^{-4} m
- (d) 1.9×10^{-5} m
- 17. The circuit shown in the figure contains two diodes each with a forward resistance of 30 Ω and with infinite backward resistance. If the battery is 3 V, the



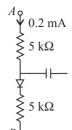
current through the 50 Ω resistance (in ampere) is

- (a) zero
- (b) 0.01
- (c) 0.02
- (d) 0.03
- 18. Which of the junction diodes shown below are forward biased?



- **19.** A potential barrier of 0.50 V exists in a p-njunction. If the depletion region is 5.0×10^{-7} m thick, what is the electric field in this region?
- (a) $1 \times 10^3 \text{ V m}^{-1}$ (b) $1.0 \times 10^6 \text{ V m}^{-1}$
- (c) $1 \times 10^2 \text{ V m}^{-1}$
- (d) $1 \times 10^4 \text{ V m}^{-1}$
- **20.** The breakdown in a reverse biased p-njunction diode is more likely to occur due to
- (a) large velocity of the minority charge carriers if the doping concentration is small
- (b) large velocity of the minority charge carriers if the doping concentration is large
- (c) strong electric field in a depletion region if the doping concentration is small
- (d) none of these
- 21. In a full wave junction diode rectifier the input ac has rms value of 20 V. The transformer used is a step up transformer having primary and secondary turn ratio 1:2. The dc voltage in the rectified output is
- (a) 12 V
- (b) 24 V (c) 36 V
- (d) 42 V

22. In a circuit as shown in the figure, if the diode forward voltage drop is 0.3 V, the voltage difference between A and B is



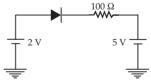
- (a) 1.3 V
- (b) 2.3 V
- (c) 0
- (d) 0.5 V
- 23. A semiconductor has equal electron and hole concentration of 6×10^8 per m³. On doping with certain impurity, electron concentration increases to 9×10^{12} per m³. The new hole concentration is
- (a) $2 \times 10^4 \text{ per m}^3$
- (b) $2 \times 10^2 \text{ per m}^2$ (d) $4 \times 10^2 \text{ per m}^3$
- (c) $4 \times 10^4 \text{ per m}^3$
- 24. A p-n photodiode is made of a material with a band gap of 2 eV. The minimum frequency of the radiation that can be absorbed by the material is nearly (Take hc = 1240 eV nm)
- (a) $1 \times 10^{14} \text{ Hz}$ (b) $20 \times 10^{14} \text{ Hz}$
- (c) $10 \times 10^{14} \text{ Hz}$
- (d) $5 \times 10^{14} \text{ Hz}$
- 25. A p-n photodiode is fabricated from a semiconductor with a band gap of 2.5 eV. The signal wavelength is
- (a) 6000 Å
- (b) 6000 nm
- (c) 4000 nm
- (d) 5000 Å
- 26. Potential barrier developed in a junction diode opposes the flow of
- (a) minority carrier in both regions only
- (b) majority carriers only
- (c) electrons in p region
- (d) holes in p region
- 27. In pure semiconductor, the number of conduction electrons is 6×10^{18} per cubic metre. How many holes are there in a sample of size $1 \text{ cm} \times 1 \text{ cm} \times 1 \text{ mm}$?
- (a) 3×10^{10}
- (b) 6×10^{11}
- (c) 3×10^{11}
- (d) 6×10^{10}
- 28. Mobilities of electrons and holes in a sample of intrinsic germanium at room temperature are $0.54 \text{ m}^2 \text{ V}^{-1} \text{ s}^{-1}$ and $0.18 \text{ m}^2 \text{ V}^{-1} \text{ s}^{-1}$ respectively. If the electron and hole densities are equal to 3.6×10^{19} m⁻³, the germanium conductivity is
- (a) 4.14 S m^{-1}
- (b) 2.12 S m^{-1}
- (c) 1.13 S m^{-1}
- (d) $5.6 \,\mathrm{S} \,\mathrm{m}^{-1}$
- 29. The probability of electrons to be found in the conduction band of an intrinsic semiconductor of finite temperature

- (a) increases exponentially with increasing band gap.
- (b) decreases exponentially with increasing
- (c) decreases with increasing temperature.
- (d) is independent of the temperature and band
- **30**. The electrical conductivity of a semiconductor increases when electromagnetic radiation of wavelength shorter than 2480 nm is incident on it. The band gap (in eV) for semiconductor is
- (a) 0.9
- (b) 0.7
- (c) 0.5
- (d) 1.1
- **31.** The following table provides the set of values of V and I obtained for a given diode. Let the characteristics to be nearly linear, over this range, the forward and reverse bias resistance of the given diode respectively are

	V	I	
Forward biasing	2.0 V	60 mA	
	2.4 V	80 mA	
Reverse biasing	0 V	0 μΑ	
	-2 V	-0.25 μΑ	

- (a) 10Ω , $8 \times 10^6 \Omega$
- (b) 20Ω , $4 \times 10^5 \Omega$
- (c) 20Ω , $8 \times 10^6 \Omega$
- (d) 10Ω , 10Ω
- **32.** The mean free path of conduction electrons in copper is about 4×10^{-8} m. The electric field which can give on an average 2 eV energy to a conduction electron in a block of copper is
- (a) $4 \times 10^6 \text{ V m}^{-1}$ (b) $5 \times 10^7 \text{ V m}^{-1}$ (c) $10 \times 10^7 \text{ V m}^{-1}$ (d) $2.5 \times 10^7 \text{ V m}^{-1}$

- (d) $2.5 \times 10^7 \text{ V m}^{-1}$
- 33. The value of ripple factor for full wave rectifier is
- (a) 41%
- (b) 141%
- (c) 48.2%
- (d) 121%
- 34. Current through the ideal diode as shown in figure is



- (a) zero

- 35. In a half wave rectifier circuit operating from 50 Hz mains frequency, the fundamental frequency in the ripple would be
- (a) 25 Hz

- (b) 50 Hz (c) 70.7 Hz (d) 100 Hz

Case Based MCQs

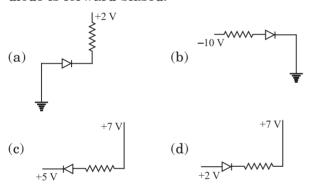
Case I: Read the passage given below and answer the following questions from 36 to 40.

Biasing of Diode

When the diode is forward biased, it is found that beyond forward voltage $V = V_k$, called knee voltage, the conductivity is very high. At this value of battery biasing for p-n junction, the potential barrier is overcome and the current increases rapidly with increase in forward voltage.

When the diode is reverse biased, the reverse bias voltage produces a very small current about a few microamperes which almost remains constant with bias. This small current is reverse saturation current.

36. In which of the following figures, the p-n diode is forward biased.

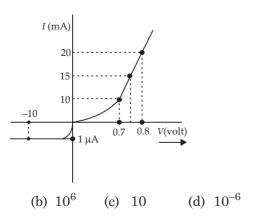


- **37.** Based on the *V-I* characteristics of the diode, we can classify diode as
- (a) bi-directional device
- (b) ohmic device

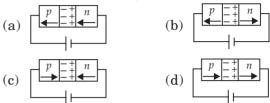
(a) 100

- (c) non-ohmic device
- (d) passive element

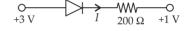
38. The *V-I* characteristic of a diode is shown in the figure. The ratio of forward to reverse bias resistance is



39. In the case of forward biasing of a p-n junction diode, which one of the following figures correctly depicts the direction of conventional current (indicated by an arrow mark)?



40. If an ideal junction diode is connected as shown, then the value of the current I is

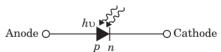


- (a) $0.013 \, A$
- (b) 0.02 A
- (c) $0.01 \,\mathrm{A}$
- (d) 0.1 A

Case II: Read the passage given below and answer the following questions from 41 to 43.

Photodiode

A photodiode is an optoelectronic device in which current carriers are generated by photons through photo-excitation *i.e.*, photoconduction by light. It is a *p-n* junction fabricated from a photosensitive semiconductor and provided with a transparent window so as to allow light to fall on its junction. A photodiode can turn its current ON and OFF in nanoseconds. So, it can be used as a fastest photo-detector.



- **41.** Photodiode is a device
- (a) which is always operated in reverse bias.
- (b) which is always operated in forward bias.
- (c) in which photocurrent is independent of intensity of incident radiation.
- (d) which may be operated in both forward or reverse bias.
- **42.** To detect light of wavelength 500 nm, the photodiode must be fabricated from a semiconductor of minimum bandwidth of
- (a) 1.24 eV
- (b) 0.62 eV
- (c) 2.48 eV
- (d) 3.2 eV

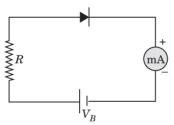
- **43.** Photodiode can be used as a photodetector to detect
- (a) optical signals
- (b) electrical signals
- (c) both (a) and (b)
- (d) none of these.

Case III: Read the passage given below and answer the following questions from 44 to 48.

p-n Junction Diode

A silicon p-n junction diode is connected to a resistor R and a battery of voltage V_R through a milliammeter (mA) as shown in figure. The knee voltage for this junction diode is $V_N = 0.7$ V. The *p-n* junction diode requires a minimum current of 1 mA to attain a value higher than the knee point on the *I-V* characteristics of this junction diode. Assuming that the voltage V across the junction is independent of the current above the knee point.

Ap-n junction is the basic building block of many semiconductor devices like diodes. Important process occurring during the formation of a *p-n* junction are diffusion and drift. In an *n*-type semiconductor concentration of electrons is more as compared to holes. In a *p*-type semiconductor concentration of holes is more as compared to electrons.



- **44.** If $V_R = 5$ V, the maximum value of R so that the voltage V is above the knee point voltage is
- (a) $40 \text{ k}\Omega$
- (b) $4.3 \text{ k}\Omega$
- (c) $5.0 \text{ k}\Omega$
- (d) $5.7 \text{ k}\Omega$
- **45.** If $V_B = 5$ V, the value of R in order to establish a current to 6 mA in the circuit is
- (a) 833Ω
- (b) 717Ω
- (c) 950Ω
- (d) 733Ω
- **46.** If $V_B = 6$ V, the power dissipated in the resistor R, when a current of 6 mA flows in the circuit is
- (a) 30.2 mW
- (b) 30.8 mW
- (c) 31.2 mW
- (d) 31.8 mW
- 47. When the diode is reverse biased with a voltage of 6 V and V_{bi} = 0.63 V. Calculate the total potential.
- (a) 9.27 V
- (b) 6.63 V
- (c) 5.27 V
- (d) 0.63 V

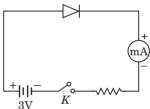
- **48.** Which of the below mentioned statement is false regarding a *p-n* junction diode?
- (a) Diodes are uncontrolled devices.
- (b) Diodes are rectifying devices.
- (c) Diodes are unidirectional devices.
- (d) Diodes have three terminals.

Case IV: Read the passage given below and answer the following questions from 49 to 52.

Potential Barrier

The potential barrier in the p-n junction diode is the barrier in which the charge requires additional force for crossing the region. In other words, the barrier in which the charge carrier stopped by the obstructive force is known as the potential barrier.

When a p-type semiconductor is brought into a close contact with n-type semiconductor, we get a p-n junction with a barrier potential of 0.4 V and width of depletion region is 4.0×10^{-7} m. This p-n junction is forward biased with a battery of voltage 3 V and negligible internal resistance, in series with a resistor of resistance R, ideal millimeter and key K as shown in figure. When key is pressed, a current of 20 mA passes through the diode.



- 49. The intensity of the electric field in the depletion region when p-n junction is unbiased
- (a) $0.5 \times 10^6 \ V \ m^{-1}$
 - (b) $1.0 \times 10^6 \text{ V m}^{-1}$
- (c) $2.0 \times 10^6 \ V \ m^{-1}$
- (d) $1.5 \times 10^6 \ V \ m^{-1}$
- **50.** The resistance of resistor R is
- (a) 150Ω
- (b) 300Ω
- (c) 130Ω
- (d) 180Ω
- 51. If the voltage of the potential barrier is V_0 . A voltage V is applied to the input, at what moment will the barrier disappear?
- (a) $V < V_0$
- (b) $V = V_0$
- (c) $V > V_0$
- (d) $V << V_0$
- **52.** If an electron with speed 4.0×10^5 m s⁻¹ approaches the p-n junction from the n-side, the speed with which it will enter the p-side is
- (a) $1.39 \times 10^5 \text{ m s}^{-1}$ (b) $2.78 \times 10^5 \text{ m s}^{-1}$
- (c) $1.39 \times 10^6 \text{ m s}^{-1}$
- (d) $2.78 \times 10^6 \text{ m s}^{-1}$



Assertion & Reasoning Based MCQs

For question numbers 53-60, two statements are given-one labelled Assertion (A) and the other labelled Reason (R). Select the correct answer to these questions from the codes (a), (b), (c) and (d) as given below.

- (a) Both A and R are true and R is the correct explanation of A
- (b) Both A and R are true but R is NOT the correct explanation of A
- (c) A is true but R is false
- (d) A is false and R is also false
- **53. Assertion** (A): The conductivity of a semiconductor increases with rise of temperature.

Reason (R): On rising temperature covalent bonds of semiconductor breaks.

54. Assertion (A) : p-n junction diode can be used even at ultra high frequencies.

Reason (R): Capacitative reactance of a p-n junction diode increases as frequency increases.

55. Assertion (A): The resistance of p-njunction is low when forward biased and is high when reverse biased

Reason (R): In reversed biased, the depletion laver is reduced.

56. Assertion (A): The direction of diffusion current in a junction diode is from *n*-region to p-region.

Reason (R): The majority current carriers diffuse from a region of lower concentration to a region of higher concentration.

57. Assertion (A): The resistivity of a semiconductor increases with temperature.

Reason (R): The atoms of a semiconductor vibrate with larger amplitude at higher temperatures thereby increasing its resistivity.

58. Assertion (A): The half-wave rectifier work only for positive half cycle of ac.

Reason (R): In half-wave rectifier only one diode is used.

59. **Assertion** (A): The ratio of free electrons to holes in intrinsic semiconductor is greater than

Reason (R): The electrons are lighter particles and holes are heavy particles.

60. Assertion (A): In a semiconductor diode, the reverse biased current is due to drift of free electrons and holes.

Reason (R): The drift of electrons and holes is due to thermal excitations.

SUBJECTIVE TYPE QUESTIONS

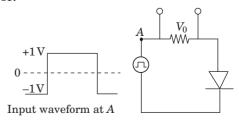


Very Short Answer Type Questions (VSA)

- 1. What is the difference between an n-type and a *p*-type extrinsic semiconductor?
- 2. What happens to the width of depletion layer of a p-n junction when it is (i) forward biased, (ii) reverse biased?
- 3. Why cannot we use Si and Ge in fabrication of visible LEDs?
- **4.** What is the function of a photodiode?
- Name the junction diode whose I-V characteristics are drawn below:



- **6.** In an *n*-type semiconductor, where does the donor energy level lies.
- 7. Can the potential barrier across a p-njunction be measured by simply connecting a voltmeter across the junction?
- 8. Draw the output waveform across the resistor.

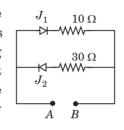


- **9.** Why are elemental dopants for Silicon or Germanium usually chosen from group XIII or group XV?
- **10.** How does an increase in doping concentration affect the width of depletion layer of a p-n junction diode?

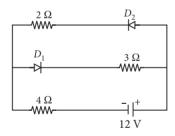


Short Answer Type Questions (SA-I)

- 11. The number densities of electrons and hole in pure Si at 27°C is 2×10^{16} m⁻³. When it is doped with indium, the hole density increases to 4×10^{22} m⁻³, find the electron density in doped silicon.
- 12. A 3 V battery may be connected across the points A and B as shown. Assuming ideal diode, find the current supplied by battery if the positive terminal of the battery is connected to the point A.

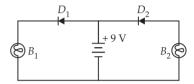


- **13.** Why photodiodes are required to operate in reverse bias? Explain.
- **14.** The circuit shown in the figure has two oppositely connected ideal diodes connected in parallel. Find the current flowing through each diode in the circuit.

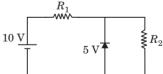


15. Draw V-I characteristics of a p-n junction diode. Explain, why the current under reverse bias is almost independent of the applied voltage up to the critical voltage.

- **16.** (a) Mention the important considerations required while fabricating a p-n junction diode to be used as a light emitting diode (LED).
- (b) What should be the order of band gap of an LED if it is required to emit light in the visible range?
- **17.** (a) In the following diagram, which bulb out of B_1 and B_2 will glow and why?



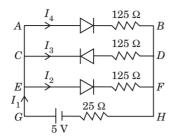
- (b) If the forward voltage in a semiconductor diode is changed from 0.5 V to 0.7 V, then the forward current changes by 1.0 mA. Find the forward resistance of diode junction.
- **18.** Three photo diodes D_1 , D_2 and D_3 are made of semiconductors having band gaps of 2.5 eV, 2 eV and 3 eV, respectively. Which ones will be able to detect light of wavelength 6000 Å?
- **19.** A *p-n* photodiode is fabricated from a semiconductor with band gap of 2.8 eV. Can it detect a wavelength of 6000 nm?
- **20.** What is the current flowing in R_2 in the circuit shown in figure? Given : R_1 = 500 Ω and R_2 = 1 k Ω





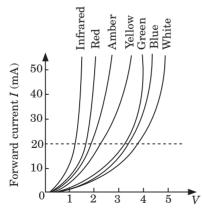
Short Answer Type Questions (SA-II)

- **21.** (a) Distinguish between n-type and p-type semiconductors on the basis of energy band diagrams.
- (b) Compare their conductivities at absolute zero temperature and at room temperature.
- **22.** Name the important process that occur during the formation of a p-n junction. Explain
- briefly, with the help of a suitable diagram, how a *p-n* junction is formed. Define the term 'barrier potential'.
- **23.** If each diode in figure has a forward bias resistance of 25 Ω and infinite resistance in reverse bias, what will be the values of the current I_1 , I_2 , I_3 and I_4 ?



- **24.** Suppose a 'n'-type wafer is created by doping Si crystal having 5×10^{28} atoms/m³ with 1 ppm concentration of As. On the surface 200 ppm Boron is added to create 'p' region in this wafer. Considering $n_i = 1.5 \times 10^{16}$ m⁻³,
- (a) Calculate the densities of the charge carriers in the n and p regions.
- (b) Comment which charge carriers would contribute largely for the reverse saturation current when diode is reverse biased.
- **25.** With the help of a simple diagram, explain the working of a silicon solar cell giving all three basic processes involved.
- **26**. **Direction**: Read the following and answer the questions given below.

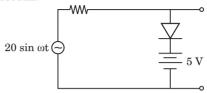
Light emitting diode is a photoelectric device which converts electrical energy into light energy. It is a heavily doped p-n junction diode which under forward biased emits spontaneous radiation. The general shape of the I-V characteristics of an LED is similar to that of a normal p-n junction diode, as shown. The barrier potentials are much higher and slightly different for each colour.



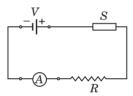
- (i) Draw the *I-V* characteristic of an LED.
- (ii) Draw the schematic symbol of light emitting diode (LED).
- (iii) An LED is constructed from a *p-n* junction

based on a certain Ga-As-P semiconducting material whose energy gap is 1.9 eV. Identify the colour of the emitted light.

(iv) Assuming the ideal diode, draw the output waveform for the circuit given in figure. Explain the waveform.



- **27.** In half-wave rectification, what is the output frequency if the input frequency is 50 Hz. What is the output frequency of a full-wave-rectifier for the same input frequency?
- **28.** In the following diagram 'S' is a semiconductor. Would you increase or decrease the value of R to keep the reading of the ammeter A constant when S is heated? Give reason for your answer.

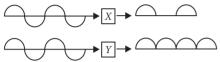


- **29.** (a) Why are Si and GaAs preferred materials for fabrication in solar cells?
- (b) Draw *V-I* characteristic of solar cell and mention its significance.
- **30.** Explain, with the help of a circuit diagram, the working of a photodiode. Write briefly how it is used to detect the optical signals.
- **31.** The number of silicon atoms per m³ is 5×10^{28} . This is doped simultaneously with 5×10^{22} atoms per m³ of Arsenic and 5×10^{20} per m³ atoms of Indium. Calculate the number of electrons and holes. Given that $n_i = 1.5 \times 10^{16}$ m⁻³. Is the material *n*-type or *p*-type?
- **32.** In the case of *n*-type Si-semiconductor, the donor energy level is slightly below the bottom of conduction band whereas in *p*-type semiconductor, the acceptor energy level is slightly above the top of valence band. Explain, giving examples, what role do these energy levels play in conduction and valence bands.



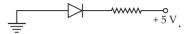
Long Answer Type Questions (LA)

- **33.** An a.c. signal is fed into two circuits 'X' and 'Y' and the corresponding output in the two cases have the waveforms as shown in figure.
- (a) Identify the circuits 'X' and 'Y'. Draw their labelled circuit diagrams.
- (b) Briefly explain the working of circuit Y.
- (c) How does the output waveform from circuit Y get modified when a capacitor is connected across the output terminals parallel to the load resistor?

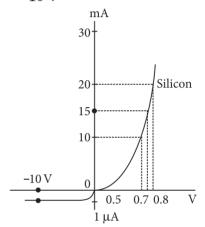


- 34. Draw the circuit arrangement for studying the *V-I* characteristics of a *p-n* junction diode in (i) forward and (ii) reverse bias. Briefly explain how the typical *V-I* characteristics of a diode are obtained and draw these characteristics.
- **35**. Draw the circuit diagram of a *p-n* diode used as a half-wave rectifier. Explain its working.

36. (a) In the following diagram, is the junction diode forward biased or reverse biased?



(b) The V-I characteristic of a silicon diode is as shown in the figure. Calculate the resistance of the diode at (i) I = 15 mA and (ii) V = -10 V



ANSWERS

OBJECTIVE TYPE QUESTIONS

- **1. (b):** When $V_A < V_{B'}$ the diode gets reverse biased and offers infinite resistance. No current flows through the upper branch
- $\therefore R = 20 \Omega$
- 2. (b): A vacancy created when an electron leaves a covalent bond. This vacancy is known as hole.
- **4. (c)**: In an unbiased p-n junction, the diffusion of charge carriers across the junction takes place from higher concentration to lower concentration. Thus, option (c) is correct.
- 5. (b): Electric field

$$E = \frac{V}{d} = \frac{0.3}{1 \times 10^{-6}} = 3 \times 10^5 \text{ V m}^{-1}$$

- **6. (b):** In p-n junction, the diffusion of majority carriers takes place when junction is forward biased and drifting of minority carriers takes place across the junction, when it is reverse biased.
- 7. **(c)**: Dynamic resistance, $r_d = \frac{\Delta V}{\Delta I}$

$$r_d = \frac{0.7 \text{ V} - 0.65 \text{ V}}{5 \times 10^{-3} \text{ A}} = \frac{0.05 \times 1000}{5} \Omega = 10 \Omega$$

(c): Since the diode is reversed biased, only drift current exists in circuit which is 20 μ A. Potential drop across 15 Ω resistor

= 15
$$\Omega \times 20 \ \mu A$$
 = 300 μV = 0.0003 V

Potential difference across the diode = 4 - 0.0003 $= 3.99 \simeq 4 \text{ V}$

- **9. (c)**: Adding fifth group element to germanium makes it an n-type semiconductor. Antimony is a fifth group element and so germanium becomes n-type semiconductor.
- 10. (c)

11. (b): Using,
$$E = E_g = \frac{hc}{\lambda} = \frac{6.6 \times 10^{-34} \times 3 \times 10^8}{589 \times 10^{-9}}$$
 J

$$= \frac{6.6 \times 10^{-34} \times 3 \times 10^8}{589 \times 10^{-9} \times 1.6 \times 10^{-19}} \text{ eV} = 2.1 \text{ eV}$$

- **14.** (a): A diode is said to be forward biased if p-type semiconductor of p-n junction is at high potential with respect to n-type semiconductor of p-n junction. It is so for circuit (a).
- **15.** (c) : The energy gap E_g depends on the temperature. For silicon, $E_g(T)=1.10-3.60\times 10^{-4}T\,{\rm eV}$

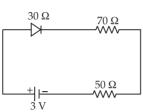
For germanium,
$$E_0(T) = 0.70 - 2.23 \times 10^{-4} T \text{ eV}$$

16. (a): Here, $E_g = 0.72 \text{ eV} = 0.72 \times 1.6 \times 10^{-19} \text{ J}$ If λ is the maximum wavelength of electromagnetic radiation

If λ is the maximum wavelength of electromagnetic radiation which can create a hole-electron pair in germanium, then

$$E_g = \frac{hc}{\lambda}$$
or $\lambda = \frac{hc}{E_g} = \frac{6.62 \times 10^{-34} \times 3 \times 10^8}{0.72 \times 1.6 \times 10^{-19}} = 1.7 \times 10^{-6} \text{ m}$

17. (c): In the circuit, the upper diode D_1 is reverse biased and the lower diode D_2 is forward biased. Thus there will be no current across upper diode junction. The effective circuit will be as shown in figure.



Total resistance of circuit

$$R = 50 + 70 + 30 = 150 \Omega$$

Current in circuit,
$$I = \frac{V}{R} = \frac{3 \text{ V}}{150 \Omega} = 0.02 \text{ A}$$

18. (a): The *p-n* junction diode is forward biased when *p* is at high potential with respect to *n*. Hence option (a) is correct.

19. (b): Electric field,
$$E = \frac{V}{C} = \frac{0.50 \text{ V}}{5 \times 10^{-7}} = 1.0 \times 10^6 \text{ V m}^{-1}$$

20. (b): In reverse biasing, the minority charge carriers will be accelerated due to reverse biasing, which on striking with atoms cause ionisation resulting in secondary electrons and thus produce more number of charge carriers.

When doping concentration is large, there will be large number of ions in the depletion region, which will give rise to a strong electric field.

21. (c) : Here, input
$$V_{\text{rms}} = 20 \text{ V}$$

Peak value of input voltage

$$V_{o} = \sqrt{2} V_{rms} = \sqrt{2} \times 20 = 28.28 V$$

Since the transformer is a step up transformer having transformer ratio 1:2, the maximum value of output voltage of the transformer applied to the diode will be

$$V_0' = 2 \times V_0 = 2 \times 28.28 \text{ V}$$

:. dc voltage =
$$\frac{2V_0'}{\pi} = \frac{2 \times 2 \times 28.28}{22/7} = 36 \text{ V}$$

22. (b): Let V be the potential difference between A and B. then

$$V - 0.3 = (5 + 5) \times 10^{3} \times (0.2 \times 10^{-3}) = 2$$

or
$$V = 2 + 0.3 = 2.3 \text{ V}$$

23. (c) : As,
$$n_e n_h = n_i^2$$

Here, $n_i = 6 \times 10^8$ per m³ and $n_e = 9 \times 10^{12}$ per m³

$$\therefore n_h = \frac{n_i}{n_0} = \frac{(6 \times 10^8)^2}{9 \times 10^{12}} = 4 \times 10^4 \text{ per m}^3$$

24. (d): Here,
$$E_a = 2 \text{ eV}$$

Wavelength of radiation corresponding to this energy is

$$\lambda = \frac{hc}{E_{cr}} = \frac{1240 \text{ eV nm}}{2 \text{ eV}} = 620 \text{ nm}$$

Frequency
$$v = \frac{c}{\lambda} = \frac{3 \times 10^8 \text{ m s}^{-1}}{620 \times 10^{-9} \text{m}} = 5 \times 10^{14} \text{ Hz}$$

25. (d): The detection occurs only when the energy of incident photon greater than or equal to the energy band gap

$$\frac{hc}{\lambda}$$
 = 2.5 eV
∴ $\lambda = \frac{hc}{2.5 \text{ eV}} = \frac{1240 \text{ eV}}{2.5 \text{ eV}} \text{nm} = 496 \text{ nm} \approx 5000 \text{ Å}$

26. (b): Potential barrier developed in a junction diode opposes the majority carriers only.

27. (b): Here,
$$n_e = 6 \times 10^{18} \text{ m}^{-3}$$

Volume of the sample = 1 cm \times 1 cm \times 1 mm = 10^{-7} m³ Number of holes in the sample = Number of electrons in the sample

$$= n_e \times V = 6 \times 10^{18} \times 10^{-7} = 6 \times 10^{11}$$

28. (a): As
$$\sigma = e(n_e\mu_e + n_h\mu_h) = en_h(\mu_e + \mu_h)$$

= 1.6 × 10⁻¹⁹ × 3.6 × 10¹⁹(0.54 + 0.18) = 4.147 S m⁻¹
29. (b)

30. (c):
$$E_g = \frac{hc}{\lambda} = \frac{1240 \text{ eV nm}}{2480 \text{ nm}} = 0.5 \text{ eV}$$

31. (c): For forward biasing.

$$\Delta V = 2.4 - 2.0 = 0.4 \text{ V}; \Delta I = 80 - 60 = 20 \text{ mA}$$

$$\therefore \quad t_{b} = \frac{\Delta V}{\Delta I} = \frac{0.4}{20 \times 10^{-3}} = 20 \,\Omega$$

For reverse biasing, $\Delta V = -2 - 0 = -2 \text{ V}$

$$\Delta I = -0.25 - 0 = -0.25 \, \mu A$$

$$r_{rb} = \frac{-2}{-0.25 \times 10^{-6}} = 8 \times 10^{6} \Omega$$

32. (b): The work done on an electron when it moves through distance, d = eEd

Work done is equal to the energy transferred to the electron

$$\therefore eEd = 2 eV$$
2 V 2 V 7

$$\Rightarrow E = \frac{2V}{Q} = \frac{2V}{4 \times 10^{-8} \text{ m}} = 5 \times 10^7 \text{ V m}^{-1}$$

33. (c) : Ripple factor for full wave rectifier = 0.482. Expressed in %, it is 48.2%.

34. (a): Here, p-n junction is reverse biased. Therefore, the current flowing through p-n junction is zero.

35. (b): Since the output voltage obtained in a half-wave rectifier circuit has single variation in one cycle of ac voltage, hence the fundamental frequency in the ripple of output voltage would be 50 Hz.

36. (c) : The *p-n* diode is forward biased when *p*-side is at a higher potential than *n*-side.

37. (c)

38. (d): Forward bias resistance,

$$R_1 = \frac{\Delta V}{\Delta I} = \frac{0.8 - 0.7}{(20 - 10) \times 10^{-3}} = \frac{0.1}{10 \times 10^{-3}} = 10$$

Reverse bias resistance, $R_2 = \frac{10}{1 \times 10^{-6}} = 10^7$

Then, the ratio of forward to reverse bias resistance,

$$\frac{R_1}{R_2} = \frac{10}{10^7} = 10^{-6}$$

39. (d): In *p*-region the direction of conventional current is same as flow of holes.

In *n*-region the direction of conventional current is opposite to the flow of electrons.

40 (c): In the given circuit the junction diode is forward biased and offers zero resistance.

$$\therefore \text{ The current, } I = \frac{3\text{ V} - 1\text{ V}}{200 \Omega} = \frac{2\text{ V}}{200 \Omega} = 0.01\text{A}$$

41. (a): Photodiode is a device which is always operated in reverse bias.

42. (c) : Let \boldsymbol{E}_g be the required bandwidth. Then

$$E_g = \frac{hc}{\lambda}$$

Here, hc=1240 eV nm, $\lambda=500$ nm

$$\therefore E_g = \frac{1240 \text{ eV nm}}{500 \text{ nm}} = 2.48 \text{ eV}$$

43. (a): A photodiode is a device which is used to detect optical signals.

44. (b): Voltage drop across *R*.

$$V_R = V_B - V_N = 5 - 0.7 = 4.3 \text{ V}$$

Here, $I_{\min} = 1 \times 10^{-3} \,\text{A}$

$$\therefore R_{\text{max}} = \frac{V_R}{I_{\text{min}}} = \frac{4.3}{1 \times 10^{-3}} = 4.3 \times 10^3 \ \Omega = 4.3 \ \text{k}\Omega$$

45. (b): $I = 6 \text{ mA} = 6 \times 10^{-3} \text{ A}$:

$$V_{R} = V_{R} - V_{N} = 5 - 0.7 = 4.3 \text{ V}$$

$$R = \frac{V_R}{I} = \frac{4.3}{6 \times 10^{-3}} = 717 \,\Omega$$

46. (d) : Here, $V_B = 6 \text{ V}$; $V_N = 0.7 \text{ V}$, $V_B = 6 - 0.7 = 5.3 \text{ V}$

Power dissipated in $R = I \times V_R$

$$= (6 \times 10^{-3}) \times 5.3 = 31.8 \times 10^{-3} \text{ W} = 31.8 \text{ mW}$$

47. (b):
$$V_t = V_{bi} + V_R = 0.63 + 6 = 6.63 \text{ V}$$

48. (d): Diode is two terminal device, anode and cathode are the two terminals.

49. (b):
$$E = \frac{V_B}{d} = \frac{0.4}{4.0 \times 10^{-7}} = 1.0 \times 10^6 \text{ V m}^{-1}$$

50. (c) : Potential difference across R = 3 - 0.4 = 2.6 V

Resistance
$$R = \frac{\text{Potential difference}}{\text{Current}} = \frac{2.6}{20 \times 10^{-3}} = 130 \ \Omega$$

51. (b): When the voltage will be the same as that of the potential barrier, the potential barrier will disappear resulting in flow of current.

52. (a):
$$\frac{1}{2}mv_1^2 = eV_B + \frac{1}{2}mv_2^2$$

$$\Rightarrow \frac{1}{2} \times (9.1 \times 10^{-31}) \times (4 \times 10^5)^2$$

$$=1.6\times10^{-19}\times(0.4)+\frac{1}{2}\times9.1\times10^{-31}\times v_2^2$$

On solving, we get

$$v_2 = 1.39 \times 10^5 \text{ m s}^{-1}$$

53. (c): At 0 K, all semiconductors are insulators. The valence band at 0 K is completely filled and there are no free electrons in conduction band. At room temperature due to thermal energy, the electron jump to the conduction band. When the temperature increases, a large number of electrons cross over the forbidden gap and jump from valence band to conduction band. Thus with rise in temperature conductivity increases. The covalent bonds of semiconductor breaks only when it is heated up extremely either by increasing temperature or by supplying strong current. After which it behaves like conductor and no longer possesses the property of low conduction, hence it is said to be damaged.

54. (c): As capacitative reactance,

$$X_C = \frac{1}{\omega C} = \frac{1}{2\pi \nu C}$$
 i.e., $X_C \propto \frac{1}{\nu}$

Thus, capacitative reactance decreases on increase in frequency.

55. (c): A small increase in forward voltage across *p-n* junction shows large increase in forward current. Hence the resistance (= voltage / current) of *p-n* junction is low when forward biased. Also the width of depletion layer of *p-n* junction decreases in forward bias.

A large increase in reverse voltage across p-n shows small increase in reverse current. Hence the resistance of p-n junction is high when reverse biased. Also the width of the depletion layer of p-n junction increases in reverse biased.

- **56. (d):** The direction of diffusion current is that when positively charged particles move from p-type to n-type of diode.
- **57. (d):** With the increase of temperature, the average energy exchanged in a collision increases and so more valence electrons can cross the energy gap, thereby increasing the electron-hole pairs. As in a semiconductor, conduction occurs

mainly through electron-hole pairs, so conductivity increases with increase of temperature. Which in turn implies that the resistivity of a semiconductor decreases with rise in temperature.

- **58.** (a): In half wave rectifier, the one diode is biased only when ac is in positive half of its cycle. For negative half of the ac cycle the diode is reversed biased and there is no output corresponding to that. Since for only one-half cycle we get a voltage output, because of which it is called half wave rectifier.
- **59. (b)**: In intrinsic semiconductor $n_e/n_h = 1$ and holes are not particles but vacancies created due to breakage of covalent bond.
- **60. (b)**: A reverse bias on a p-n junction opposes the movement of the majority charge carriers thus stopping the diffusion current. It makes the free electrons and holes to drift cross the junction. Therefore a small current in μ A flows even when the p-n junction is reverse biased. The drift current is due to the thermal excitations of the electrons and holes.

SUBJECTIVE TYPE QUESTIONS

1.

	<i>n</i> -type Semiconductor	<i>p</i> -type Semiconductor	
(i)	It is formed by doping pentavalent impurities.	It is formed by doping trivalent impurities.	
(ii)	The electrons are majority carriers and holes are minority carriers. $(n_e >> n_h)$	The holes are majority carriers and electrons are minority carriers. $(n_h >> n_e)$	

- **2.** (i) Forward biased : As forward voltage opposes the potential barrier and effective barrier potential decreases. It makes the width of the depletion layer smaller.
- (ii) Reverse biased: As reverse voltage supports the potential barrier and effective barrier potential increases. It makes the width of the depletion layer larger.
- **3.** LED's must have band gap in the order of 1.8 eV to 3 eV but Si and Ge have band gap less than 1.8 eV.
- **4.** Photodiode is used to detect the light signal and to measure light intensity.
- **5.** The junction diode is solar cell.
- **6. (b):** In *n*-type semiconductor, the donor energy level lies just below the conduction band.
- **7.** No, the voltmeter should have a very high resistance as compared to the resistance of p-n junction, which is nearly infinite.



The diode acts as half wave rectifier, it offers low resistance when forward biased and high resistance when reverse biased.

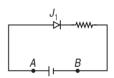
- **9.** Size of the dopant atom should be compatible in the pure semiconductor and contribute a charge carrier by forming covalent bond with Si or Ge atoms. Elemental dopants from group XIII and group XV fulfil this condition.
- **10.** When there is an increase in doping concentration, the applied potential difference causes an electric field which acts opposite to the potential barrier. This results in reducing the potential barrier and hence the width of depletion layer decreases.
- 11. For extrinsic or doped semiconductor

$$n_e \cdot n_h = n_i^2 \Rightarrow n_e = \frac{n_i^2}{n_h}$$

Here $n_i = 2 \times 10^{16} \text{ m}^{-3}$ and $n_h = 4 \times 10^{22} \text{ m}^{-3}$

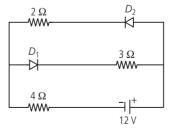
$$\Rightarrow n_e = \frac{(2 \times 10^{16} \,\mathrm{m}^{-3})^2}{4 \times 10^{22} \,\mathrm{m}^{-3}} = 10^{-10} \,\mathrm{m}^{-3}.$$

12. If A is positive and B is negative, J_1 is forward biased and J_2 is reverse biased, so effective current is



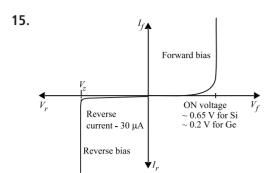
$$\Rightarrow$$
 $i_a = 0.3 \text{ A}.$

- **13.** In reverse bias condition of photodiode, the change in saturation reverse current is directly proportional to the change in the incident light flux or light intensity, which can be measured accurately. It is not so when photodiode is forward biased.
- **14.** Diode D_1 is reverse biased, so it offers an infinite resistance. So no current flows in the branch of diode D_1 .



Diode D_2 is forward biased, and offers negligible resistance in the circuit. So current in the branch

$$I = \frac{V}{R_{eq}} = \frac{12V}{2\Omega + 4\Omega} = 2A$$



The reverse current is due to minority charge carriers and even a small voltage is sufficient to sweep the minority carriers from one side of the junction to the other side of the junction. Here the current is not limited by the magnitude of the applied voltage but is limited due to the concentration of the minority carrier on either side of the junction.

- **16.** (a) (i) There is very little resistance to limit the current in LED. Therefore, a resistor must be used in series with the LED to avoid any damage to it.
- (ii) The reverse breakdown voltages of LEDs are very low, typically around 5 V. So care should be taken while fabricating a p-n-junction diode so that the p side should only attached to the positive of battery and vice versa as LED easily get damaged by a small reverse voltage.
- (b) The semiconductor used for fabrication of visible LEDs must have at least a band gap of 1.8 eV because spectral range of visible light is about 0.4 mm to 0.7 mm, *i.e.*, about 3 eV to 1.8 eV.
- **17.** (a) Bulb B_1 will glow, as diode D_1 is forward biased. Bulb B_2 will not glow as diode D_2 is reverse biased.

(b) Forward resistance =
$$\frac{\Delta V}{\Delta I}$$

 $\therefore \frac{\Delta V}{\Delta I} = \frac{0.7 - 0.5}{1.0 \times 10^{-3}} = 200 \ \Omega.$

18. We know that, energy of incident photon, $E = \frac{hc}{\lambda}$ $\lambda = 6000 \text{ Å} = 600 \text{ nm} \text{ (given)}$

$$E = \frac{1242 \text{ eV nm}}{600 \text{ nm}} = 2.07 \text{ eV}$$

 D_2 will detect these radiations because energy of incident radiation is greater than the band gap.

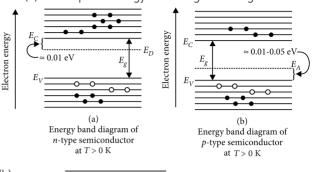
19. Energy of the incident photon with a band gap of 6000 nm.

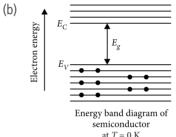
$$E = \frac{hc}{\lambda} J = \frac{hc}{e\lambda} eV = \frac{6.63 \times 10^{-34} \times 3 \times 10^8}{1.6 \times 10^{-19} \times 6 \times 10^{-6}} = 0.207 \text{ eV}$$

The photodiode need an energy of 2.8 eV to give response to incident light.

As $E < E_{g'}$ the given photodiode cannot detect the radiation of wavelength 6000 nm.

- **20.** The diode is reverse biased, but the voltage across it is given as 5 V. R_2 is in parallel with the diode, so current in $R_2 = \frac{5 \text{ V}}{1000 \Omega}$ \Rightarrow Current in $R_2 = 5 \text{ mA}$.
- **21.** (a) The required energy band diagrams are given below:





At absolute zero temperature (0 K), conduction band of semiconductor is completely empty, *i.e.*, $\sigma = 0$. Hence the semiconductor behaves as an insulator. At room temperature, some valence electrons acquire enough thermal energy and jump to the conduction band where they are free to conduct electricity. Thus the semiconductor acquires a small conductivity at room temperature.

22. Two processes that take place in the formation of a *p-n* junction are diffusion and drift.

	p	← /	$_{0}$	•	n	
•	0	0 -	+	•	•	0
0	0	0 -	+	•	•	•
0	0	0 -	+	•	0	•
0	•	0 -	+	•	•	•

When p-n junction is formed, then at the junction, free electrons from n-type diffuse over to p-type, thereby filling in the holes in p-type. Due to this a layer of positive charge is built on n-side and a layer of negative charge is built on p-side of the p-n junction. This layer sufficiently grows up within a very short time of the junction being formed, preventing any further movement of charge carriers (i.e., electrons and holes) across the junction. Thus a potential difference V_0 of the order of 0.1 to 0.3 V is set up across the p-n junction called potential barrier or junction barrier. The thin region around the

junction containing immobile positive and negative charges is known as depletion layer.

23. Let *R* be the effective resistance of the circuit, then

$$R = R_{AB} || R_{EF} + 25$$

$$R_{AB} = 125 + 25 = 150 \Omega$$

$$R_{EF} = 125 + 25 = 150 \Omega$$

$$\therefore R = 25 + \frac{150}{2} = 100 \Omega$$

Since diode in the branch *CD* is reverse biased. $I_3 = 0$.

Current,
$$I_1 = \frac{5}{100} = 0.05 \text{ A}$$

According to Kirchhoff's current rule,

$$I_{1} = I_{2} + I_{3} + I_{4} \text{ or } I_{2} + I_{4} = I_{1} = 0.05$$

$$\therefore R_{AB} = R_{EF}, \text{ so, } I_{4} = I_{2}$$

$$2I_{4} = 2I_{2} = 0.05$$

$$I_{4} = I_{2} = \frac{0.05}{2} = 0.025 \text{ A}$$

24. (a) For *n*-type region,

$$n_e = N_D = \frac{1}{10^6} \times 5 \times 10^{28} = 5 \times 10^{22} \text{ m}^{-3}$$

$$\left(\because 1 \text{ ppm} = \frac{1}{10^6}\right)$$
As $n_e n_h = n_i^2$,
$$n_h = \frac{n_i^2}{n_e} = \frac{(1.5 \times 10^{16} \text{ m}^{-3})^2}{5 \times 10^{22} \text{ m}^{-3}} = 0.45 \times 10^{10} \text{ m}^{-3}$$

For *p*-type region

$$n_h = N_A = \frac{200}{10^6} \times 5 \times 10^{28} = 1 \times 10^{25} \text{ m}^{-3}$$
Now, $n_e = \frac{n_i^2}{n_h} = \frac{(1.5 \times 10^{16} \text{ m}^{-3})^2}{1 \times 10^{25} \text{ m}^{-3}} = 2.25 \times 10^7 \text{ m}^{-3}$

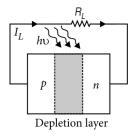
- (b) The minority carrier holes of n-region wafer $(n_h = 0.45 \times 10^{10} \text{ m}^{-3})$ would contribute more to reverse saturation current than minority carrier electrons of p-region wafer $(n_e = 2.25 \times 10^7 \text{ m}^{-3})$ when p n junction is reverse biased
- **25.** Principle: A solar cell works on the principle of photovoltaic effect according to which when light photons of energy greater than energy band gap of a semiconductor are incident on p-n junction of that semiconductor, electron-hole pairs are generated which give rise to an emf.

Generation of emf: Three basic processes are involved in the generation of emf by a solar cell when solar radiations are incident on it. These are:

- (i) The generation of electron-hole pairs close to the junction due to incidence of light with photo energy $h_0 \ge E_h$.
- (ii) The separation of electrons and holes due to the electric field of the depletion region. So, electrons are swept to *n*-side

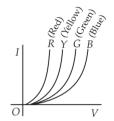
and holes to p-side.

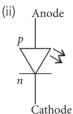
(iii) The electrons reaching the *n*-side are collected by the front contact and holes reaching *p*-side are collected by the back contact. Thus, *p*-side becomes positive and *n*-side become negative giving rise to a photovoltage.



When an external load R_L is connected as shown in figure, a photocurrent I_I begins to flow through the load.

26. (i) The *I-V* characteristics of an LED is similar to that of a Si junction diode. But the threshold voltages are much higher and slightly different for each colour.





(iii) As
$$E_g = \frac{hc}{\lambda}$$
 $\therefore \lambda = \frac{hc}{E_g}$

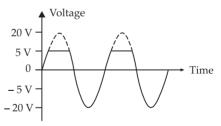
Here, $E_g = 1.9 \text{ eV}$, hc = 1240 eV nm

$$\therefore \lambda = \frac{1240 \text{ eV nm}}{1.9 \text{ eV}} = 652.6 \text{ nm}$$

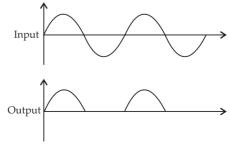
Hence, the emitted light is of red colour.

(iv) For the voltage less than 5 V, the diode is reverse biased and circuit will act as open circuit.

When input voltage is greater than 5 V, diode is in conducting state.



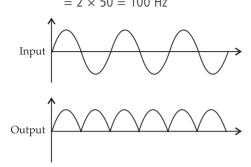
27. In half wave rectification, only one ripple is obtained per cycle in the output.



Output frequency of a half wave rectifier = input frequency = 50 Hz

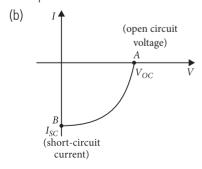
In full wave rectification, two ripples are obtained per cycle in the output.

Output frequency = $2 \times \text{input frequency}$ = $2 \times 50 = 100 \text{ Hz}$



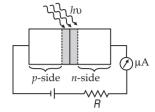
- **28.** We will increase the value of *R*. On heating a semiconductor, its resistance decreases with rise in temperature. As the semiconductor, *S* is in series, so net resistance of the circuit also decreases. So by increasing the value of *R* we can keep the resistance of circuit constant and hence the current in the circuit or the reading of ammeter *A* can be kept constant.
- **29.** (a) The energy for the maximum intensity of the solar radiation is nearly 1.5 eV. In order to have photo excitation the energy of radiation ($h_{\rm O}$) must be greater than energy band gap (E_g), i.e., $h_{\rm O} > E_g$. Therefore, the semiconductor with energy band gap about 1.5 eV or lower and with higher absorption coefficient, is likely to give better solar conversion efficiency.

The energy band gap for Si is about 1.1 eV, while for GaAs, it is about 1.53 eV. The gas GaAs is better inspite of its higher bandgap than Si because it absorbs relatively more energy from the incident solar radiations being of relatively higher absorption coefficient.



- (i) *V-I* curve is drawn in the fourth quadrant, because a solar cell does not draws current but supply current to the load.
- (ii) In V-I curve, the point A indicates the maximum voltage V_{OC} being supplied by the given solar cell when no current is being drawn from it. V_{OC} is called the open circuit voltage.

- (iii) In V-I curve, the point B indicates the maximum current I_{SC} which can be obtained by short circuiting the solar cell without any load resistance. I_{SC} is called the short circuit current
- **30.** Working of photodiode: A junction diode made from light sensitive semiconductor is called a photodiode. A photodiode is a *p-n* junction diode arranged in reverse biasing.



The number of charge carriers increases when light of suitable frequency is made to fall on the p-n junction, because new electron-hole pairs are created by absorbing the photons of suitable frequency. Intensity of light controls the number of charge carriers. Due to this property photodiodes are used to detect optical signals.

31. We know that for each atom doped with Arsenic, one free electron is received. Similarly, for each atom doped with indium, a vacancy is created.

So, the number of free electrons introduced by pentavalent impurity added,

$$n_e = N_{As} = 5 \times 10^{22} \text{ m}^{-3}$$

The number of holes introduced by trivalent impurity added

$$n_h = N_{\rm ln} = 5 \times 10^{20} \, \rm m^{-3}$$

We know the relation, $n_e n_h = n_i^2$...(i)

Now net electrons,

$$n'_e = n_e - n_h = 5 \times 10^{22} - 5 \times 10^{20}$$

= $4.95 \times 10^{22} \text{ m}^{-3}$...(ii)

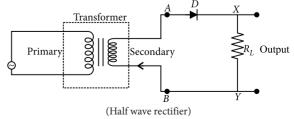
Now using equation (i), net holes

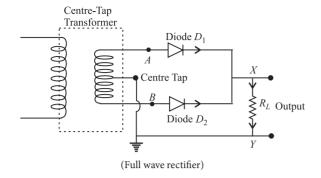
$$n'_h = \frac{n_i^2}{n'_e} = \frac{(1.5 \times 10^{16})^2}{4.95 \times 10^{22}} = 4.5 \times 10^9 \text{ m}^{-3}$$

So, $n'_{e} >> n'_{h}$ the material is of *n*-type.

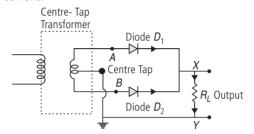
- **32.** In *n*-type extrinsic semiconductors, the number of free electrons in conduction band is much more than the number of holes in valence band. The donor energy level lies just below the conduction band. In *p*-type extrinsic semiconductor, the number of holes in valence band is much more than the number of free electrons in conduction band. The acceptor energy level lies just above the valence band.
- **33.** (a) X = Half wave rectifier

Y = Full wave rectifier





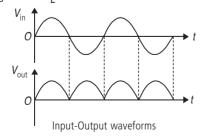
(b) Two p-n junction diodes can be used to make full wave rectifier which is used to convert alternating current into direct current.



A full wave rectifier consists of two diodes connected in parallel across the ends of secondary winding of a center tapped step down transformer. The load resistance R_L is connected across secondary winding and the diodes between A and B as shown in the circuit.

During positive half cycle of input a.c., end A of the secondary winding becomes positive and end B negative. Thus diode D_1 becomes forward biased, whereas diode D_2 reverse biased. So diode D_1 allows the current to flow through it, while diode D_2 does not, and current in the circuit flows from D_1 and through load D_2 from D_1 from D_2 through load D_2 from D_2 from D_2 from D_3 fro

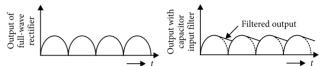
During negative half cycle of input a.c., end A of the secondary winding becomes negative and end B positive, thus diode D_1 becomes reverse biased, whereas diode D_2 forward biased. So diode D_1 does not allow the current to flow through it but diode D_2 does, and current in the circuit flows from D_2 and through load R_1 from X to Y.



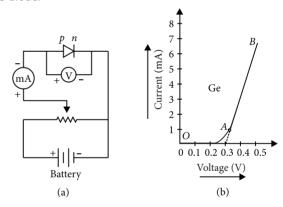
Since in both the half cycles of input a.c., electric current through load R_L flows in the same direction, so d.c. is obtained across R_L . Although direction of electric current

through R_L remains same, but its magnitude changes with time, so it is called pulsating d.c.

(c) A capacitor of large capacitance is connected in parallel to the load resistor R_L . When the pulsating voltage supplied by the rectifier is rising, the capacitor C gets charged. If there is no external load, the capacitor would have remained charged to the peak voltage of the rectified output. However, when there is no load and the rectified voltage starts falling, the capacitor gets discharged through the load and the voltage across capacitor begins to fall slowly.

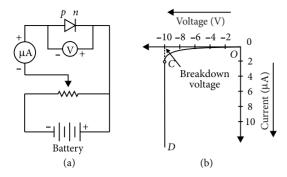


34. Forward biased characteristics: The circuit diagram for studying forward biased characteristics is shown in the figure. Starting from a low value, forward bias voltage is increased step by step (measured by voltmeter) and forward current is noted (by ammeter). A graph is plotted between voltage and current. The curve so obtained is the forward characteristic of the diode.



At the start when applied voltage is low, the current through the diode is almost zero. It is because of the potential barrier, which opposes the applied voltage. Till the applied voltage exceeds the potential barrier, the current increases very slowly with increase in applied voltage (*OA* portion of the graph). With further increase in applied voltage, the current increases very rapidly (*AB* portion of the graph), in this situation, the diode behaves like a conductor. The forward voltage beyond which the current through the junction starts increasing rapidly with voltage is called threshold or cut-in voltage. If line *AB* is extended back, it cuts the voltage axis at potential barrier voltage.

Reverse biased characteristics: The circuit diagram for studying reverse biased characteristics is shown in the figure.

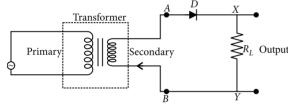


In reverse biased, the applied voltage supports the flow of minority charge carriers across the junction. So, a very small current flows across the junction due to minority charge carriers.

Motion of minority charge carriers is also supported by internal potential barrier, so all the minority carriers cross over the junction.

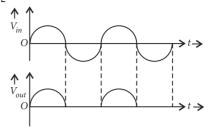
Therefore, the small reverse current remains almost constant over a sufficiently long range of reverse bias, increasing very little with increasing voltage (*OC* portion of the graph). This reverse current is voltage independent upto certain voltage known as breakdown voltage and this voltage independent current is called reverse saturation current.

35. Half wave rectifier:



It consists of a diode D connected in series with load resistor R_L across the secondary windings of a step-down transformer.

Primary of transformer is connected to a.c. supply. During positive half cycle of input a.c., end A of the secondary winding becomes positive and end B negative. Thus, diode D becomes forward biased and conducts the current through it. So, current in the circuit flows from A to B through load resistor B_I .



During negative half cycle of input a.c., end A of the secondary winding becomes negative and end B positive. Thus, diode D becomes reverse biased and does not conduct any current. So, no current flows in the circuit. Since electric current through load R_L flows only during positive half cycle, in one direction only *i.e.*, from A to B, so d.c. is obtained across R_L .

36. (a) Voltage at p side is less than voltage at n side of the diode so it is in reverse bias.

(b) (i) From the given curve, we have voltage, V = 0.8 volt for current, I = 20 mA voltage, V = 0.7 volt for current, I = 10 mA $\Rightarrow \Delta I = (20 - 10)$ mA $= 10 \times 10^{-3}$ A $\Rightarrow \Delta V = (0.8 - 0.7) = 0.1$ V

$$\therefore \text{ Resistance, } R = \frac{\Delta V}{\Delta I} \Rightarrow R = \frac{0.1}{10 \times 10^{-3}} \Rightarrow R = 10 \Omega$$

(ii) For V = -10 V, we have

$$I = -1 \ \mu A = -1 \times 10^{-6} \ A \Rightarrow R = \frac{10}{1 \times 10^{-6}} = 1.0 \times 10^7 \ \Omega$$